


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/661,952	LEE ET AL.	
	Examiner	Art Unit	
	Edward Wojciechowicz	2815	

SEARCHED			
Class	Subclass	Date	Examiner
257	328, 329, 331	3-15-05	EJ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
257	328, 329, 331	3-15-05	EJ

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR